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*           AIS31 evaluation tests           *
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date, time:    01/23/2015, 15:39:17
tested file:   prg610_0c.rnd
size of file: 10240000 bytes
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Introduction  
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The purpose of the following tests is to evaluate the suitability of a true (physical) random number generator for cryptographic applications. In [1] an evaluation methodology for physical random number generators has been proposed by the German Federal Security Agency. In the mathematical-technical reference to [1], five tests are defined for the P2-evaluation of a physical random number generator (cf. [3] and [4]) which are implemented in the following tests 1 - 5.

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Results of test 1 (test (P2.i)(vii.a) of AIS 31, cf. [3] and [4])  
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In this test, the relative frequency  $r$  of bit 1 occurring in the first 100000 bits of the bit sequence is computed. Then the bit sequence passes the test if  $|r - 0.5| < 0.025$ .

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test scope: first 100000 bits
number of ones: 50009
relative frequency: 0.500090
test value: 0.00009000 < 0.025
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sequence passes test 1

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Results of test 2 (test (P2.i)(vii.b) of AIS 31, cf. [3] and [4])  
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In this test, two disjoint sub-sequences  $TF(0)$  and  $TF(1)$  of bit pairs are considered where  $TF(i)$  consists of the first 100000 bit pairs of the form  $(i,x)$  occurring in the bit sequence after the test scope of test 1. Let  $v(i,j)$  denote the relative frequency of all bit pairs of the form  $(i,j)$  in  $TF(i)$ . Then the bit sequence passes the test if  $|v(0,1) + v(1,0) - 1| < 0.02$ .

```
number of 2-bit words looked up: 200217
relative frequency v(0,1): 0.500820
relative frequency v(1,0): 0.500510
test value: 0.00133000 < 0.02
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sequence passes test 2

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Results of test 3 (test (P2.i)(vii.c) of AIS 31, cf. [3] and [4])  
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In this test, 4 disjoint sub-sequences  $TF(0,0), \dots, TF(1,1)$  of 3-tupels are considered where  $TF(i,j)$  consists of the first 100000 3-tupels of bits of the form  $(i,j,x)$  occurring in the bit sequence after the test scope of test 2. For every  $i,j$  in  $\{0,1\}$ , let  $S(i,j)$  denote the sub-sequence of all bits  $k$  such that  $(i,j,k)$  is element of  $TF(i,j)$ . Then sample  $S(0,j)$  is compared with  $S(1,j)$  for every  $j = 0,1$ . In this context, a comparison of two bit sequences  $g$  and  $h$  of equal length is performed by a computation of the test value  $t = (g_0 - h_0)^2 / (g_0 + h_0) + (g_1 - h_1)^2 / (g_1 + h_1)$  where  $g_i$  resp.  $h_i$  is the number of bit  $i$  occurring in sequence  $g$  resp.  $h$ . Let  $t_j$  be the test value for the comparison of  $S(0,j)$  with  $S(1,j)$ . Then the bit sequence passes the test if  $t_j < 15,13$  for  $j = 0,1$ .

number of 3-bit words looked up: 401037  
test value  $t_1$ : 0.027380  $\leq$  15.13  
test value  $t_2$ : 0.162000  $\leq$  15.13

sequence passes test 3

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Results of test 4 (test (P2.i)(vii.d) of AIS 31, cf. [3] and [4])  
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In this test, 8 disjoint sub-sequences  $TF(0,0,0), \dots, TF(1,1,1)$  of 4-tupels are considered where  $TF(i,j,k)$  consists of the first 100000 4-tupels of bits of the form  $(i,j,k,x)$  occurring in the bit sequence after the test scope of test 3. For every  $i,j$  in  $\{0,1\}$ , let  $S(i,j,k)$  denote the sub-sequence of all bits  $b$  such that  $(i,j,k,b)$  is an element of  $TF(i,j,k)$ . Then sample  $S(0,j,k)$  is compared with  $S(1,j,k)$  for every  $j,k$  of  $\{0,1\}$ . In this context, a comparison of two bit sequences  $g$  and  $h$  of equal length is performed by a computation of the test value  $t = (g_0 - h_0)^2 / (g_0 + h_0) + (g_1 - h_1)^2 / (g_1 + h_1)$  where  $g_i$  resp.  $h_i$  is the number of bit  $i$  occurring in sequence  $g$  resp.  $h$ . Let  $t_{jk}$  be the test value for the comparison of  $S(0,j,k)$  with  $S(1,j,k)$ . Then the bit sequence passes the test if  $t_{jk} < 15,13$  for all  $j,k$  of  $\{0,1\}$ .

number of 4-bit words looked up: 802995  
test value  $t_{00}$ : 0.343223  $\leq$  15.13  
test value  $t_{01}$ : 1.635924  $\leq$  15.13  
test value  $t_{10}$ : 2.217781  $\leq$  15.13  
test value  $t_{11}$ : 1.740506  $\leq$  15.13

sequence passes test 4

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Results of test 5 (test (P2.i)(vii.e) of AIS 31, cf. [3] and [4])  
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In this test, the Coron test with the parameters  $L = 8$ ,  $Q = 2560$ , and  $K = 256000$  is performed (cf. [2]). For the first  $Q+K$  8-bit-words after the test scope of test 4, the test value  $f$  of the Coron test is computed. The bit sequence passes the test if  $f > 7.976$ .

8-bit words looked up: 2560 + 256000 bytes  
f-value: 8.00305043  
8.00305043  $>$  7.976

sequence passes test 5

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## References

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- [1] AIS 31: Functionality Classes and Evaluation Methodology for Physical Random Number Generators. Version 1 (25.09.2001), (mandatory if a German IT security certificate is applied for; English translation).  
available at [www.bsi.bund.de/zertifiz/zert/interpr/ais31e.pdf](http://www.bsi.bund.de/zertifiz/zert/interpr/ais31e.pdf)
  
- [2] J.- S. Coron: On the Security of Random Sources. In: Public Key Cryptography - PKC 99. Lecture Notes in Computer Science, Vol. 1560, 29-42, Springer-Verlag, 2002.
  
- [3] W. Killmann and W. Schindler: A Proposal for: Functionality Classes and Evaluation Methodology for True (Physical) Random Number Generators. Version 3.1 (25.09.2001), mathematical-technical reference of [1] (English Translation);  
available at [www.bsi.bund.de/zertifiz/zert/interpr/trngk31e.pdf](http://www.bsi.bund.de/zertifiz/zert/interpr/trngk31e.pdf)
  
- [4] W. Schindler and W. Killmann: Evaluation Criteria for True (Physical) Random Number Generators Used in Cryptographic Applications. In: Cryptographic Hardware and Embedded Systems - CHES 2002. Lecture Notes in Computer Science, Vol. 2523, 431-449, Springer-Verlag, 2002.